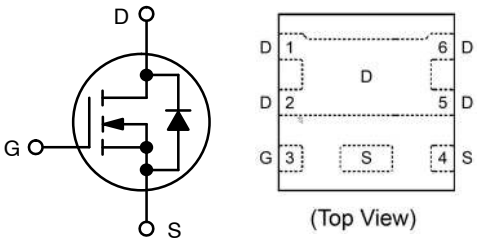
# MOSFET - Power, Single N-Channel
## 30 V, 13 mΩ, 35 A

# NVLJWS013N03CL

| $V_{(BR)DSS}$ | $R_{DS(on)}$ MAX | $I_D$ MAX |
|---|---|---|
| 30 V | 13 mΩ @ 10 V | 35 A |
| | 18 mΩ @ 4.5 V | |

### Features
- Small Footprint for Compact Design
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low $Q_G$ and Capacitance to Minimize Driver Losses
- Wettable Flank Option for Enhanced Optical Inspection
- AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free and are RoHS Compliant

### ELECTRICAL CONNECTION




N−CHANNEL MOSFET

### MAXIMUM RATINGS ($T_J$ = 25°C unless otherwise noted)

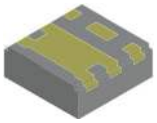
| Parameter | | | Symbol | Value | Unit |
|---|---|---|---|---|---|
| Drain−to−Source Voltage | | | $V_{DSS}$ | 30 | V |
| Gate−to−Source Voltage | | | $V_{GS}$ | ±20 | V |
| Continuous Drain Current $R_{\theta JC}$ (Notes 1, 3) | Steady State | $T_C$ = 25°C | $I_D$ | 35 | A |
| | | $T_C$ = 100°C | | 25 | |
| Power Dissipation $R_{\theta JC}$ (Note 1) | | $T_C$ = 25°C | $P_D$ | 27 | W |
| | | $T_C$ = 100°C | | 13 | |
| Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2, 3) | Steady State | $T_A$ = 25°C | $I_D$ | 10 | A |
| | | $T_A$ = 100°C | | 7 | |
| Power Dissipation $R_{\theta JA}$ (Notes 1, 2) | | $T_A$ = 25°C | $P_D$ | 2.4 | W |
| | | $T_A$ = 100°C | | 1.2 | |
| Pulsed Drain Current | $T_A$ = 25°C, $t_p$ = 10 μs | | $I_{DM}$ | 116 | A |
| Operating Junction and Storage Temperature Range | | | $T_J$, $T_{stg}$ | −55 to +175 | °C |
| Source Current (Body Diode) | | | $I_S$ | 22 | A |
| Single Pulse Drain−to−Source Avalanche Energy ($I_{L(pk)}$ = 2.2 A) | | | $E_{AS}$ | 29 | mJ |
| Lead Temperature for Soldering Purposes (1/8″ from case for 10 s) | | | $T_L$ | 260 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---|---|---|---|
| Junction−to−Case − Steady State | $R_{\theta JC}$ | 5.6 | °C/W |
| Junction−to−Ambient − Steady State (Note 2) | $R_{\theta JA}$ | 63 | |

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Surface−mounted on FR4 board using a 650 $mm^2$, 2 oz. Cu pad.
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



WDFNW6 (2.05x2.05)
CASE 515AD

### MARKING DIAGRAM


XXXX = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week

### ORDERING INFORMATION
See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

**ELECTRICAL CHARACTERISTICS** ($T_J$ = 25°C unless otherwise noted)

| Parameter | Symbol | Test Condition | | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|
| **OFF CHARACTERISTICS** | | | | | | | |
| Drain−to−Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}$ = 0 V, $I_D$ = 250 μA | | 30 | | | V |
| Drain−to−Source Breakdown Voltage Temperature Coefficient | $V_{(BR)DSS}/T_J$ | $I_D$ = 250 μA, ref to 25°C | | | 13.5 | | mV/°C |
| Zero Gate Voltage Drain Current | $I_{DSS}$ | $V_{GS}$ = 0 V, $V_{DS}$ = 30 V | $T_J$ = 25°C | | | 1 | μA |
| | | | $T_J$ = 125°C | | | 10 | |
| Gate−to−Source Leakage Current | $I_{GSS}$ | $V_{DS}$ = 0 V, $V_{GS}$ = 20 V | | | | 100 | nA |
| **ON CHARACTERISTICS** (Note 4) | | | | | | | |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS}$ = $V_{DS}$, $I_D$ = 250 μA | | 1.2 | | 2.0 | V |
| Threshold Temperature Coefficient | $V_{GS}/T_J$ | $I_D$ = 250 μA, ref to 25°C | | | −4.5 | | mV/°C |
| Drain−to−Source On Resistance | $R_{DS(on)}$ | $V_{GS}$ = 10 V, $I_D$ = 8 A | | | 11 | 13 | mΩ |
| | | $V_{GS}$ = 4.5 V, $I_D$ = 8 A | | | 15 | 18 | |
| Forward Transconductance | $g_{FS}$ | $V_{DS}$ = 10 V, $I_D$ = 8 A | | | 27 | | S |
| **CHARGES AND CAPACITANCES** | | | | | | | |
| Input Capacitance | $C_{iss}$ | $V_{GS}$ = 0 V, $V_{DS}$ = 15 V, f = 1.0 MHz | | | 600 | | pF |
| Output Capacitance | $C_{oss}$ | | | | 350 | | |
| Reverse Transfer Capacitance | $C_{rss}$ | | | | 10 | | |
| Total Gate Charge | $Q_{G(TOT)}$ | $V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V; $I_D$ = 8 A | | | 4 | | nC |
| Total Gate Charge | $Q_{G(TOT)}$ | $V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_D$ = 8 A | | | 10 | | |
| Threshold Gate Charge | $Q_{G(TH)}$ | | | | 1.1 | | |
| Gate−to−Source Charge | $Q_{GS}$ | | | | 2.0 | | |
| Gate−to−Drain Charge | $Q_{GD}$ | | | | 0.8 | | |
| Plateau Voltage | $V_{GP}$ | | | | 2.9 | | V |
| **SWITCHING CHARACTERISTICS** (Note 5) | | | | | | | |
| Turn−On Delay Time | $t_{d(on)}$ | $V_{GS}$ = 10 V, $V_{DD}$ = 15 V, $I_D$ = 8 A, $R_G$ = 6 Ω | | | 7 | | ns |
| Rise Time | $t_r$ | | | | 2 | | |
| Turn−Off Delay Time | $t_{d(off)}$ | | | | 18 | | |
| Fall Time | $t_f$ | | | | 3 | | |
| **DRAIN−SOURCE DIODE CHARACTERISTICS** | | | | | | | |
| Forward Diode Voltage | $V_{SD}$ | $V_{GS}$ = 0 V, $I_S$ = 8 A | $T_J$ = 25°C | | 0.84 | 1.2 | V |
| | | | $T_J$ = 125°C | | 0.71 | | |
| Reverse Recovery Time | $t_{RR}$ | $V_{GS}$ = 0 V, $dI_S/dt$ = 100 A/μs, $I_S$ = 8 A | | | 24 | | ns |
| Charge Time | $t_a$ | | | | 11.8 | | |
| Discharge Time | $t_b$ | | | | 12 | | |
| Reverse Recovery Charge | $Q_{RR}$ | | | | 11 | | nC |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

## TYPICAL CHARACTERISTICS

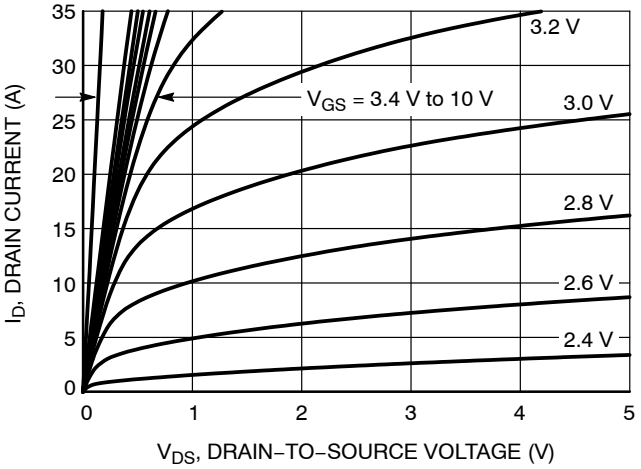



**Figure 1. On−Region Characteristics**

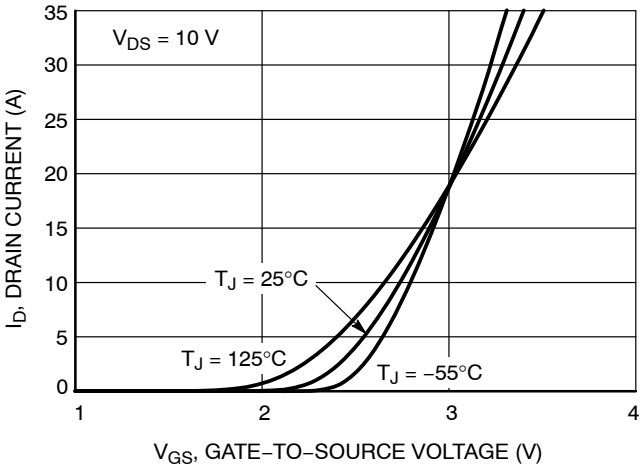



**Figure 2. Transfer Characteristics**

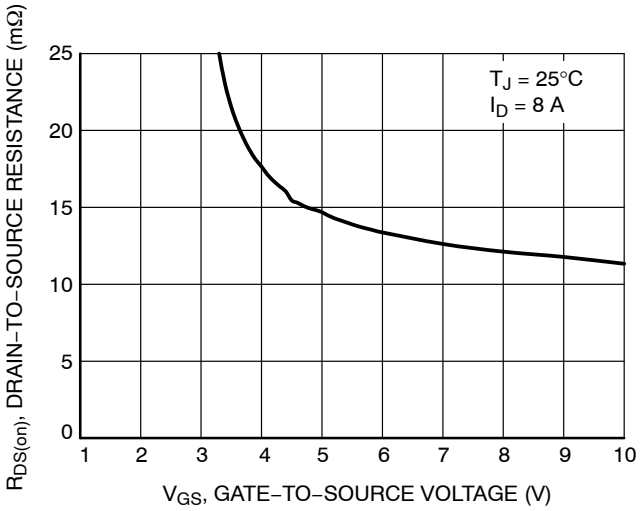



**Figure 3. On−Resistance vs. Gate−to−Source Voltage**

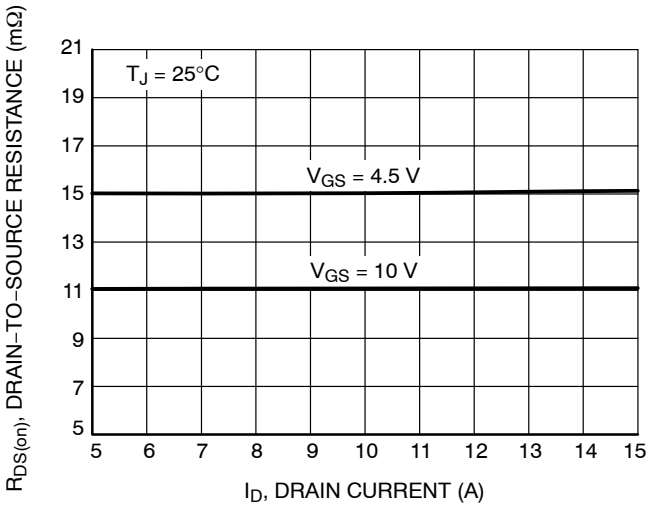



**Figure 4. On−Resistance vs. Drain Current and Gate Voltage**

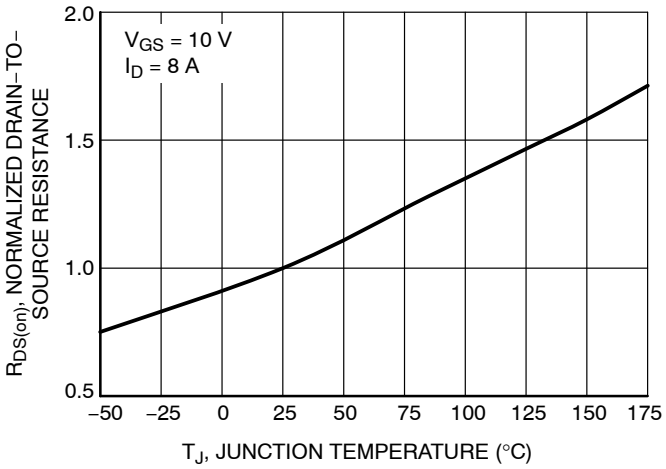



**Figure 5. On−Resistance Variation with Temperature**

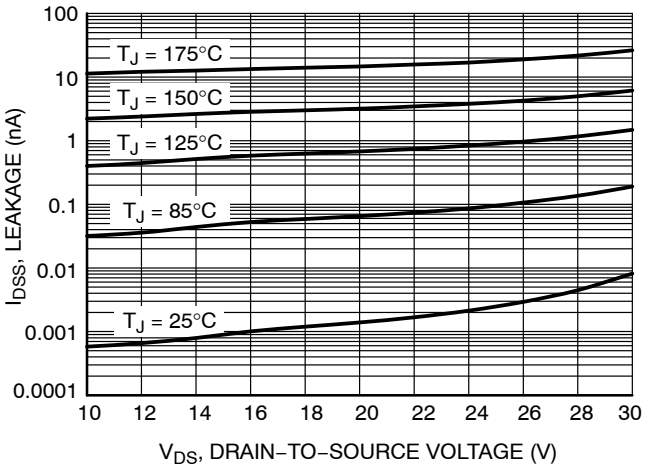



**Figure 6. Drain−to−Source Leakage Current vs. Voltage**

## TYPICAL CHARACTERISTICS

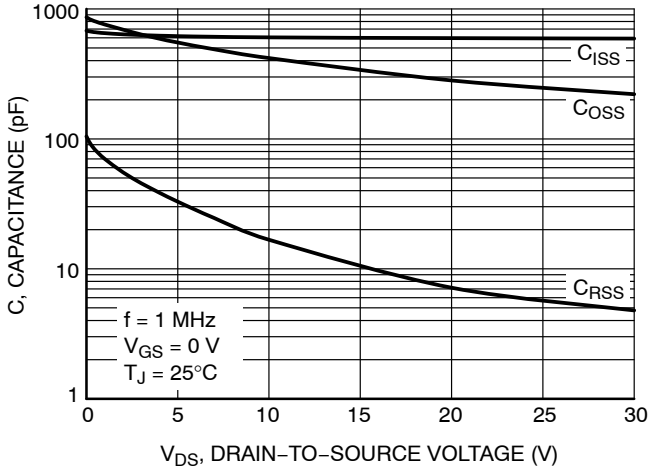



**Figure 7. Capacitance Variation**

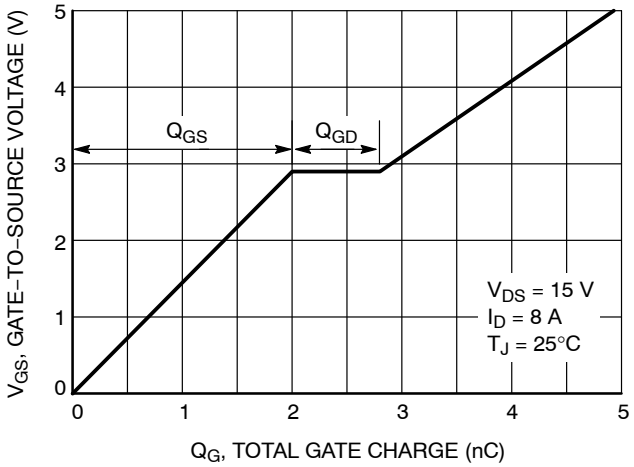



**Figure 8. Gate−to−Source vs. Total Charge**

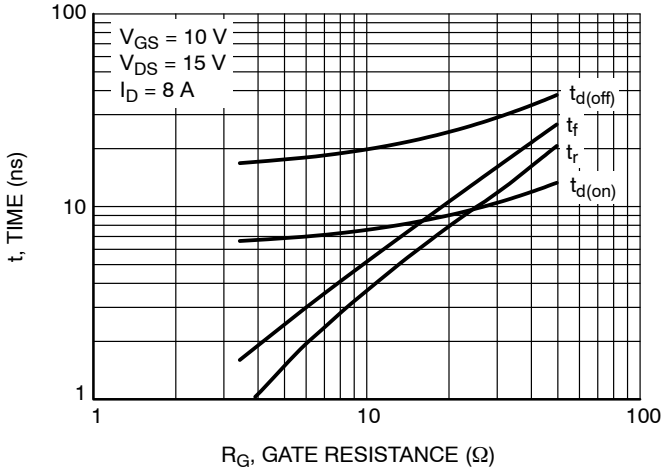



**Figure 9. Resistive Switching Time Variation vs. Gate Resistance**

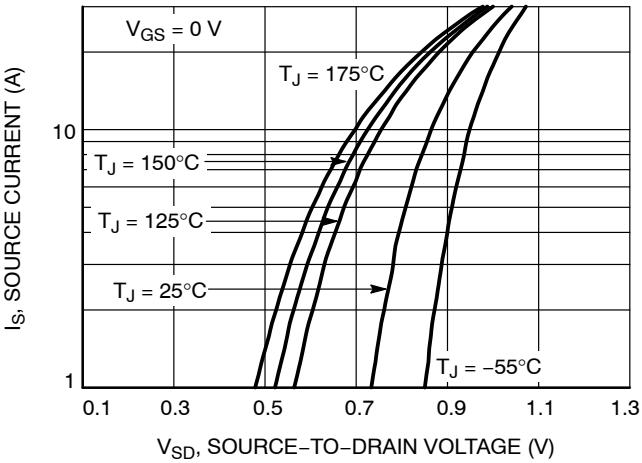



**Figure 10. Diode Forward Voltage vs. Current**

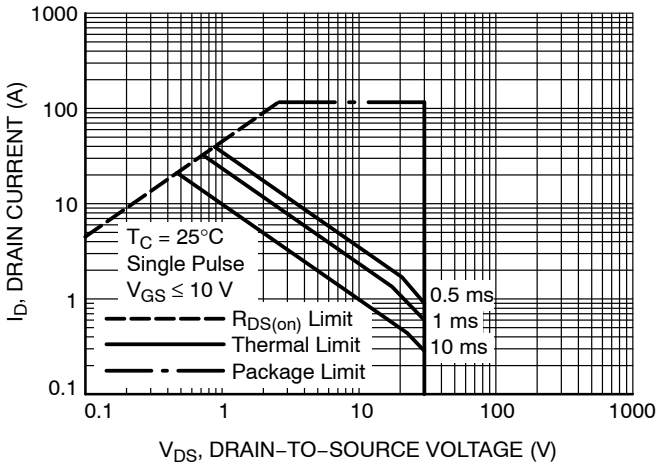



**Figure 11. Maximum Rated Forward Biased Safe Operating Area**

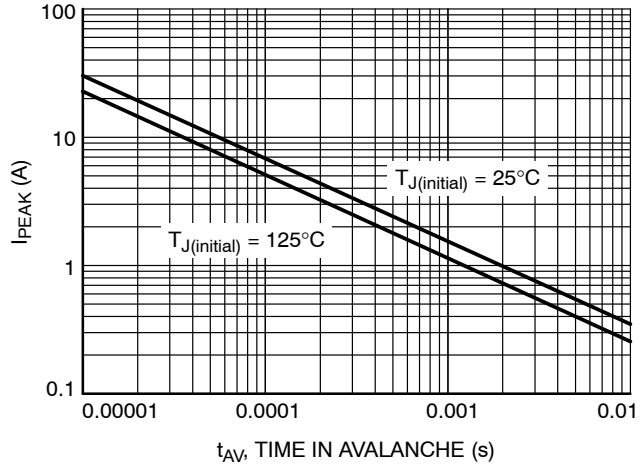



**Figure 12. Maximum Drain Current vs. Time in Avalanche**

## TYPICAL CHARACTERISTICS

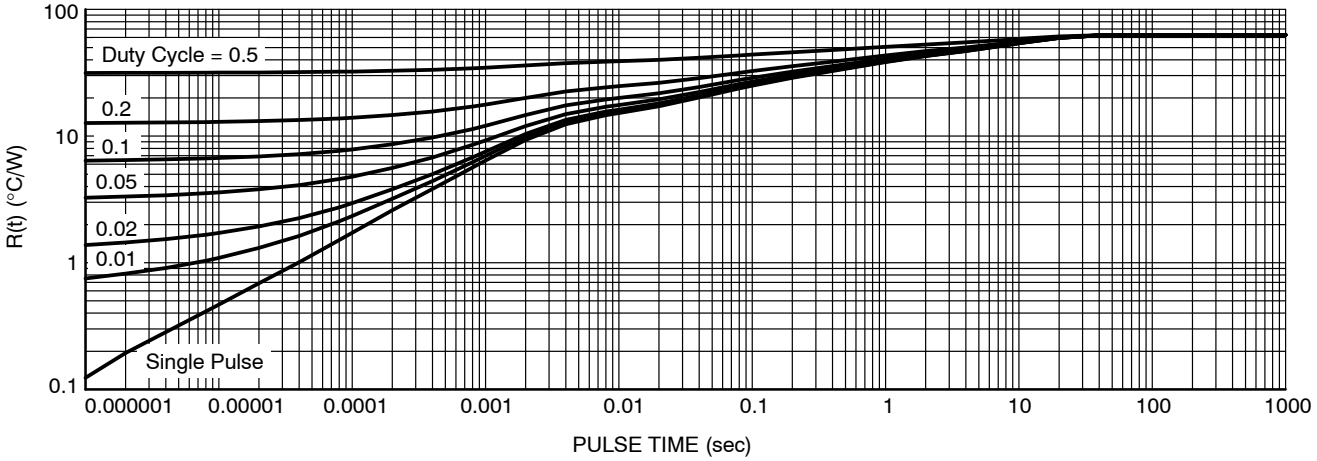



**Figure 13. Transient Thermal Impedance**

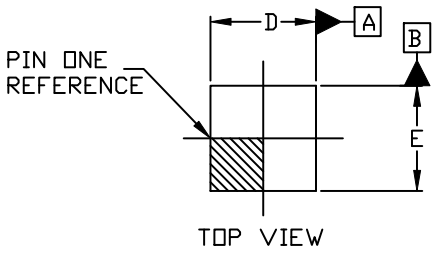
### DEVICE ORDERING INFORMATION

| Device | Marking | Package | Shipping† |
|---|---|---|---|
| NVLJWS013N03CLTAG | 013N | WDFNW6<br>(Pb−Free, Wettable Flanks) | 3000 / Tape & Reel |

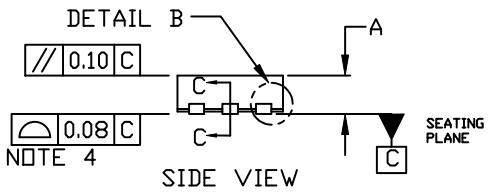
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

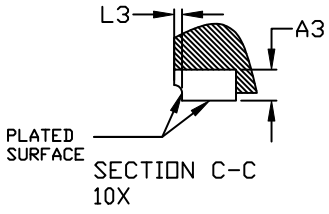
## PACKAGE DIMENSIONS

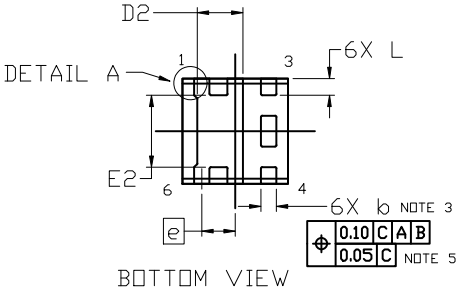
**WDFNW6 2.05x2.05, 0.65P**
CASE 515AD
ISSUE O

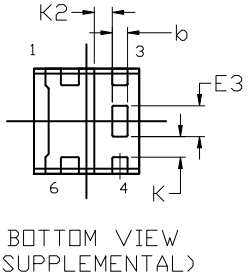



NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b APPLIES TO PLATED TERMINALS AND IS MEASURED BETWEEN 0.15 AND 0.30MM FROM THE TERMINAL TIP.
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
5. POSITIONAL TOLERANCE APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

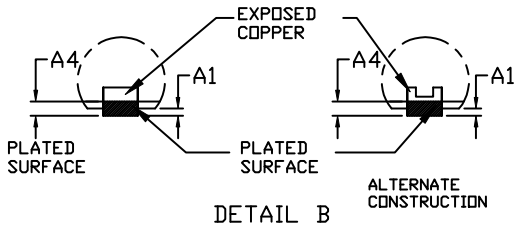


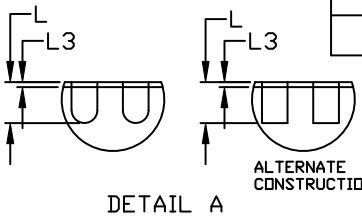



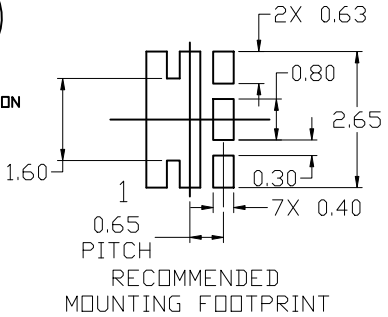




| DIM | MILLIMETERS | | |
|---|---|---|---|
| | MIN. | NOM. | MAX. |
| A | 0.70 | 0.75 | 0.80 |
| A1 | 0.00 | --- | 0.05 |
| A3 | | 0.20 REF | |
| A4 | 0.10 | --- | --- |
| b | 0.25 | 0.30 | 0.35 |
| D | 1.95 | 2.05 | 2.15 |
| D2 | 0.84 | 0.89 | 0.94 |
| E | 1.95 | 2.05 | 2.15 |
| E2 | 1.35 | 1.40 | 1.45 |
| E3 | 0.55 | 0.60 | 0.65 |
| e | | 0.65 BSC | |
| K | | 0.40 REF | |
| K2 | | 0.35 REF | |
| L | 0.275 | 0.325 | 0.375 |
| L3 | --- | --- | 0.09 |




* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## PUBLICATION ORDERING INFORMATION

**LITERATURE FULFILLMENT**:
**Email Requests to:** orderlit@onsemi.com

**onsemi Website:** www.onsemi.com

**TECHNICAL SUPPORT**
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Phone: 011 421 33 790 2910

**Europe, Middle East and Africa Technical Support:**
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For additional information, please contact your local Sales Representative

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